

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
		Examiner Nizal S. Chandrakumar	Art Unit 1625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	G	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-57088455	11-1980	JP	Yoshio et al.	CO3G 5/04
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	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
*	U	Bader et al. Proceedings of SPIE-The international Society for Optical Engineering, 2001, Vol. 4461, pages 304-310.		
	V			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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